

Cleaning of Parasitic Bunches in Booster Rings

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Why?

- **Arbitrary patterns with high purity**
- **Compatibility with top-off**
(Compatibility top-off “2 bunches”)
- **Cleaning at lower energies**

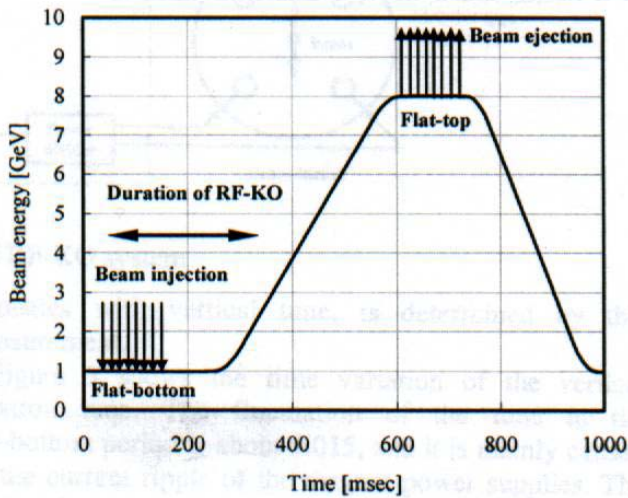
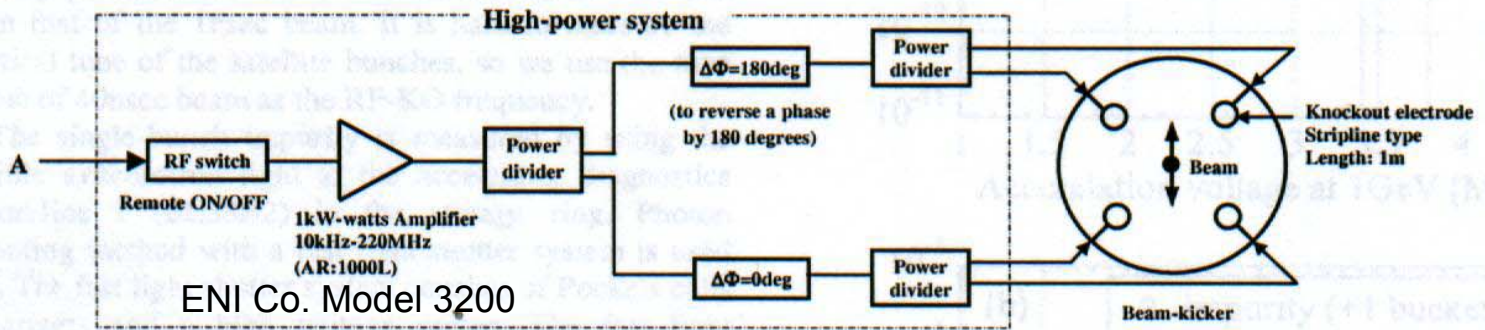
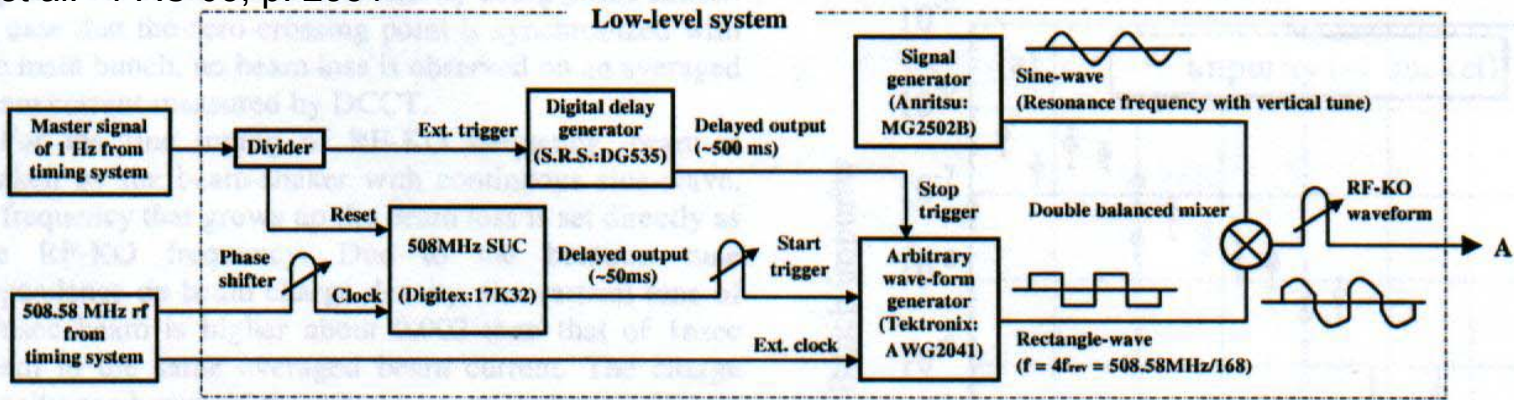
Necessary Conditions

Parasitic bunches have to be generated only during the injection of the booster or in the first phase of the energy ramping (before cleaning)

No leakage during the final part of the energy ramping (after cleaning) and during the storage ring injection

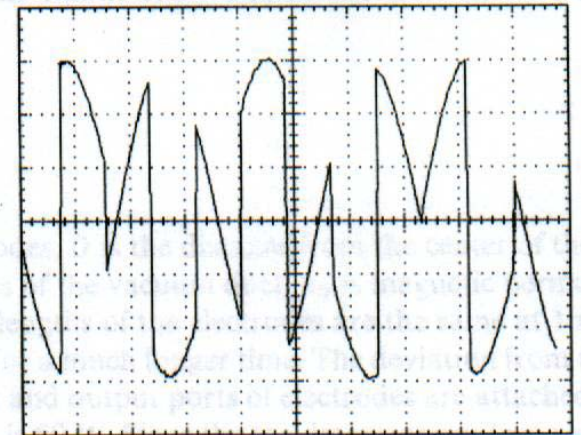
SPRING 8 Case

T. Aoki et al. - PAC 03, p. 2551



re 2: Block diagram of RF-KO system

Purity <math>< 10^{-6}</math>



Time (200 ns/div.)

ESRF Case: Cleaning During Ramping

ESRF:

$f_{RF} = 352.2 \text{ MHz}$

$f_{CI} = 180.0 \text{ kHz}$

10 Hz Injec. Rate

Injec. Energy = 200 MeV

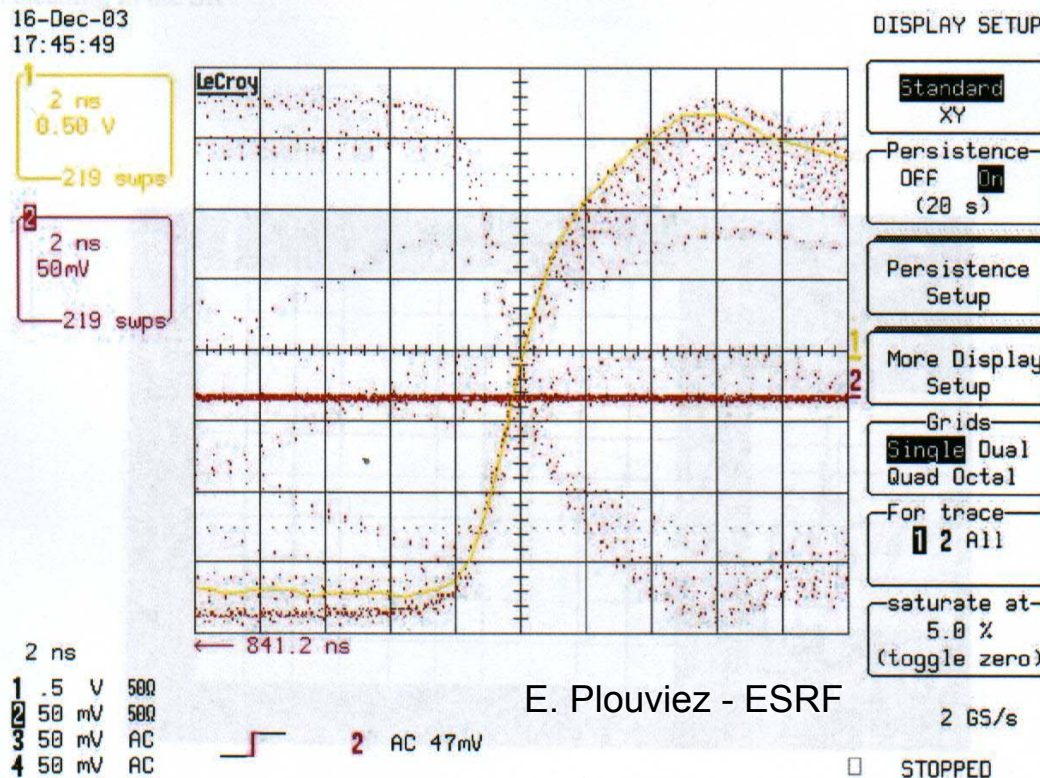
Extrac. Energy = 6 GeV

$E_c = 300 \text{ MeV} \sim 5 \text{ ms}$ after injection

Chromaticity & Tune optimized at 300 MeV

Continuous excitation

Purity < 10^{-6}



2 Amplifiers:
RFPA
100 W
0.1 - 200 MHz

and BESSY II ...

Power Requirement

H. Suzuki et al, NIM A 444 (2000) 515-533:

$$\Delta z \cong \frac{1}{2} \frac{\Delta\theta \frac{\tau_d}{T_0} (\beta_K \beta_{MAX})^{1/2}}{\left[1 + \left(2\pi \frac{\tau_d}{T_0} \Delta v_z \right)^2 \right]^{1/2}} \quad z = x, y$$

$\tau_d \gg T_0 :$

$$\Delta z \sim \frac{\Delta\theta (\beta_K \beta_{MAX})^{1/2}}{4\pi \Delta v_z} \quad z = x, y$$

$$\Delta\theta_y = \frac{2e}{\gamma mc} B_x L$$

Stripline Kicker:

$$B_x = \frac{\mu_0}{\sqrt{2\pi}} \frac{1}{D} \left(1 - \frac{D^2}{R^2} \right) I$$

$$P = Z I^2$$

Stripline Kicker

$$B_x = \frac{\mu_0}{\sqrt{2\pi}} \frac{1}{D} \left(1 - \frac{D^2}{R^2} \right) I$$

$$D = 46.1 \text{ mm}$$

$$R = 60.0 \text{ mm}$$

$$Z = 50 \ \Omega$$

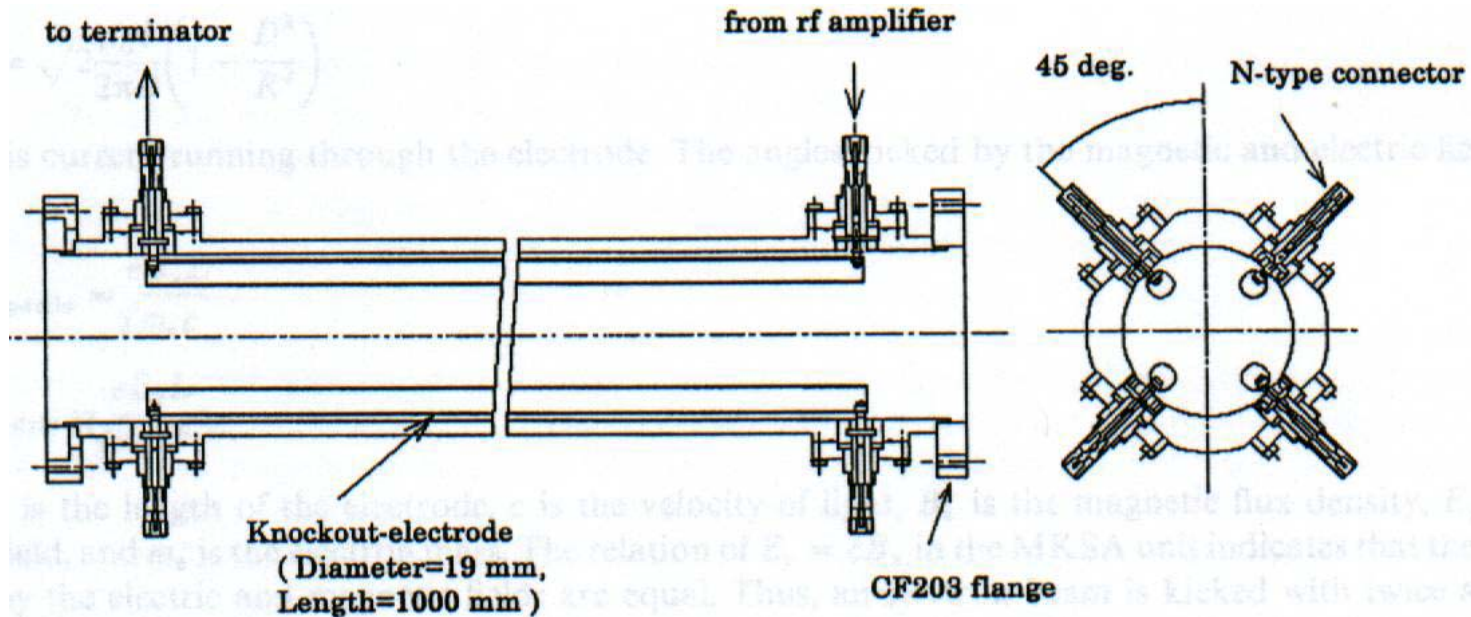


Fig. 6. Cross-sectional view of RFKO electrodes.

ALS Booster Case: Amplifier Power

$$T_0 = 250.2 \text{ ns}$$

$$\tau_T \sim 800 \text{ ms @ 300 MeV}$$

$$\beta_{MAX} = 11.6 / 11.6 \text{ m (x/y)}$$

$$\Delta z_{VC} = 30.0 / 22.0 \text{ mm (x/y)}$$

$$v'_{z0} = -10.51 / -4.810 \text{ (x/y)}$$

$$\beta_{MAX} = \beta_K = 11.6 \text{ m}$$

$$\Delta y_{VC} = 22.0 \text{ mm}$$

$$\frac{\Delta E}{E} \sim 1 \times 10^{-4} \text{ @ 300 MeV}$$

$$\tau_L \sim 400 \text{ ms @ 300 MeV}$$

$$v'_y = \pm 0.1 \Rightarrow \Delta v_y (\Delta p/p = 0.005) \sim 5 \times 10^{-4}$$

$$\Delta \theta_y (\Delta v_y = 0.0005) \sim 12 \text{ } \mu\text{rad}$$

$$B_x L \sim 6 \times 10^{-6} \text{ Tm @ 300 MeV}$$

$$L = .55 \text{ m} \Rightarrow B_x \sim 1.1 \times 10^{-5} \text{ T}$$

$$I \sim 4.3 \text{ A} \Rightarrow P = ZI^2 \sim 93 \text{ W}$$

ALS Booster Case: Amplifier Bandwidth

$$\tau_{Rise} \leq 1.6 \text{ ns} \quad \Rightarrow \quad BW \sim 200 \text{ MHz}$$

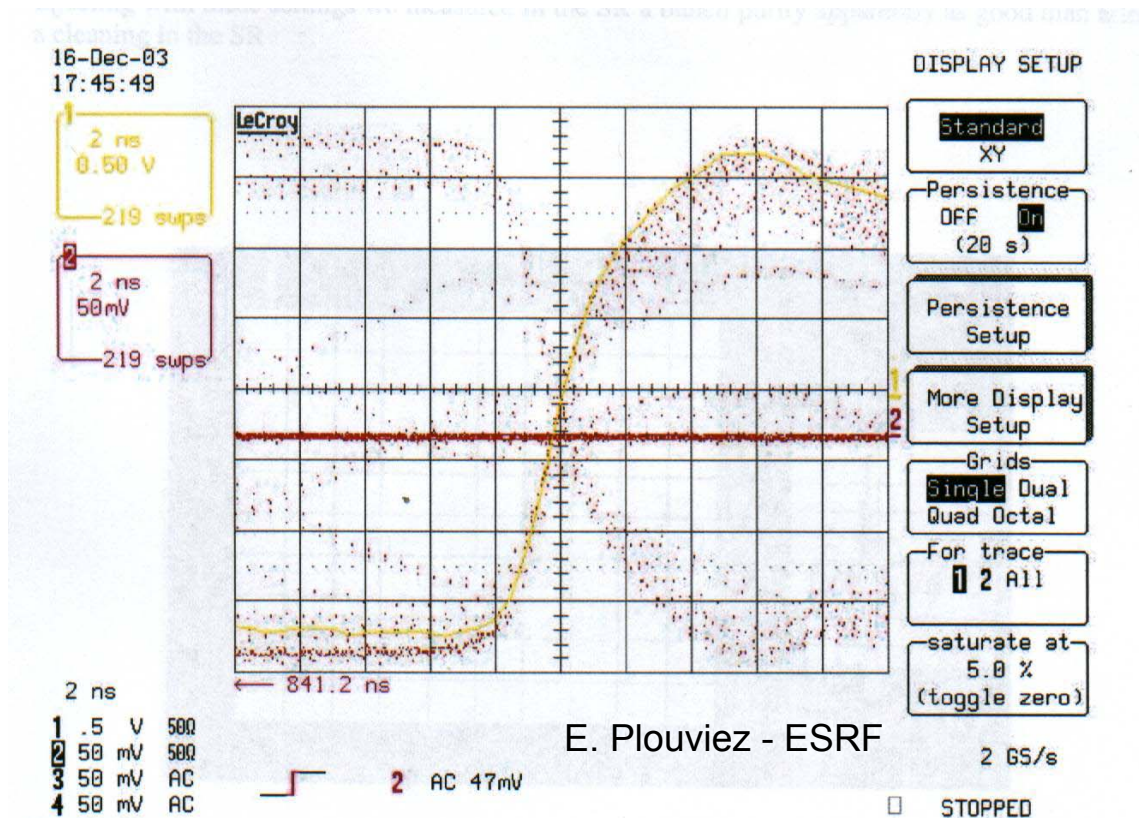


Figure 3: horizontal time variation during the first 10 ns after injection

ALS Booster Case: Synchrotron Frequency Excitation

$$f_0 = 3.997 \text{ MHz}$$

$$\nu_x = 6.264$$

$$\nu_y = 2.789$$

$$f_{\beta x} = \begin{cases} (n + 0.264)f_0 \\ ((n + 1) - 0.264)f_0 \end{cases} \quad (n = 0, 1, 2, \dots) \quad \Rightarrow \quad f_{\beta x} = 1.055 \text{ MHz}$$

$$f_{\beta y} = \begin{cases} (n + 0.789)f_0 \\ ((n + 1) - 0.789)f_0 \end{cases} \quad (n = 0, 1, 2, \dots) \quad \Rightarrow \quad f_{\beta y} = 0.843 \text{ MHz}$$

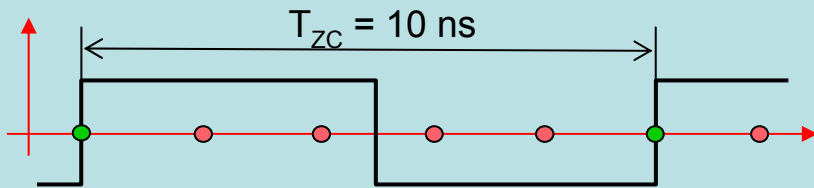
ALS Booster Case: Zero crossing signal

Square Wave (equispaced bunches):

1 bunch $f_{ZC} = f_0 \sim 4$ MHz

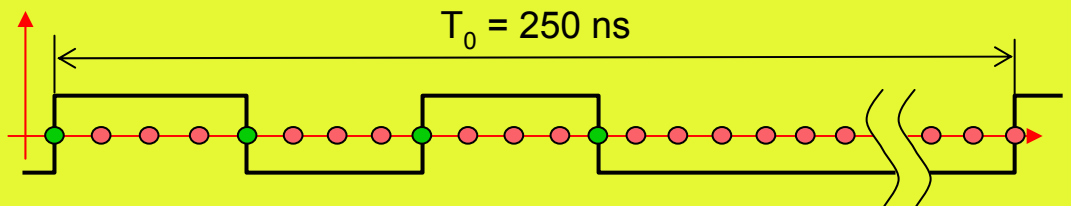
5 bunches $f_{ZC} = 5f_0 \sim 20$ MHz

25 bunches $f_{ZC} = 25f_0 \sim 100$ MHz



**Arbitrary Function Generator
with BW > 500 MHz**

*Example: Booster multibunch injection:
4 bunches from the linac*



Main Components & Requirements

- **200 W, 200 MHz BW class A Amplifier (TFB spare?)**
- **Stripline Kicker (TWE ?)**
- **Tune pickup (TWE ?)**
- **Photon Counting System for the storage ring**
- **Arbitrary Function Generator with BW > 500 MHz**
- **Vertical Scraper ?**

- **Tune measurement system**
- **Chromaticity correction ($\sim \pm 0.1$)**
- **Possibility of storing beam in the booster.**
Characterization and tune of the system.
- **Possibility of testing the system in the Storage
Ring**